

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/647,516 | Applicant(s)/Patent Under Reexamination KOJIMA, HIDEAKI | |
| | Examiner Steven S. Paik | Art Unit 2876 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-5,955,970 A | 09-1999 | Ando et al. | 340/928 |
| | B | US-5,926,546 A | 07-1999 | Maeda et al. | 705/65 |
| | C | US-6,019,285 A | 02-2000 | Isobe et al. | 235/384 |
| | D | US-5,310,999 A | 05-1994 | Claus et al. | 235/384 |
| | E | US-6,690,293 B2 | 02-2004 | Amita, Kozo | 340/928 |
| | F | US-5,532,689 A | 07-1996 | Bueno, Serge | 340/928 |
| | G | US-2002/0115410 | 08-2002 | Higashino et al. | 455/41 |
| | H | US-2004/0004120 | 01-2004 | Kojima, Hideaki | 235/384 |
| | I | US-5,206,495 | 04-1993 | Kreft, H. D. | 235/492 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.